

Notice of References Cited	Application/Control No. 10/002,309	Applicant(s)/Patent Under Reexamination WELCH ET AL.	
	Examiner Tekchand Saidha	Art Unit 1652	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Makino et al. [DNA Research 5 : 1-9, (1998)] {including sequence search alignment between T43121 and SEQ ID NO : 2)
	V	Sequence search alignment between Q9ZAL1 (5.1.1999) and SEQ ID NO : 2 (residue 24-886).
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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